

TEMIC

Siliconix

SUP/SUB60N06-18

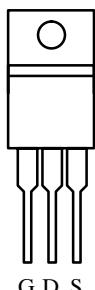
N-Channel Enhancement-Mode Transistors

175°C Maximum Junction Temperature

Product Summary

$V_{(BR)DSS}$ (V)	$r_{DS(on)}$ (Ω)	I_D (A)
60	0.018	60

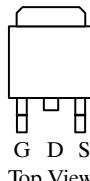
TO-220AB



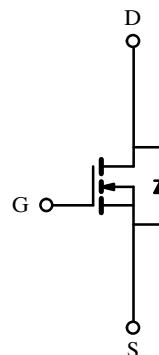
Top View

SUP60N06-18

TO-263



SUP60N06-18



N-Channel MOSFET

Absolute Maximum Ratings ($T_C = 25^\circ\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	± 20	
Continuous Drain Current ($T_J = 175^\circ\text{C}$)	I_D	60	A
$T_C = 100^\circ\text{C}$		39	
Pulsed Drain Current	I_{DM}	120	
Avalanche Current	I_{AR}	60	
Repetitive Avalanche Energy ^a	E_{AR}	180	mJ
Power Dissipation	P_D	120 ^b	W
$T_A = 25^\circ\text{C}$ (TO-220AB and TO-263)		3.7	
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 to 175	°C

Thermal Resistance Ratings

Parameter	Symbol	Limit	Unit
Junction-to-Ambient	R_{thJA}	40	°C/W
PCB Mount (TO-263) ^c		62.5	
Junction-to-Case	R_{thJC}	1.25	

Notes:

a. Duty cycle $\leq 1\%$.

b. See SOA curve for voltage derating.

c. When mounted on 1" square PCB (FR-4 material).

Specifications ($T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_{DS} = 1 \text{ mA}$	2.0		4.0	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
		$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125^\circ\text{C}$			50	
		$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 175^\circ\text{C}$			150	
On-State Drain Current ^b	$I_{D(\text{on})}$	$V_{DS} = 5 \text{ V}, V_{GS} = 10 \text{ V}$	60			A
Drain-Source On-State Resistance ^b	$r_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}$		0.014	0.018	Ω
		$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}, T_J = 125^\circ\text{C}$		0.024	0.030	
		$V_{GS} = 10 \text{ V}, I_D = 30 \text{ A}, T_J = 175^\circ\text{C}$		0.031	0.036	
Forward Transconductance ^b	g_{fs}	$V_{DS} = 15 \text{ V}, I_D = 30 \text{ A}$		49		S
Dynamic^a						
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$		2000		pF
Output Capacitance	C_{oss}			400		
Reversen Transfer Capacitance	C_{rss}			115		
Total Gate Charge ^c	Q_g	$V_{DS} = 30 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 60 \text{ A}$		39	60	nC
Gate-Source Charge ^c	Q_{gs}			12		
Gate-Drain Charge ^c	Q_{gd}			10		
Turn-On Delay Time ^c	$t_{d(\text{on})}$	$V_{DD} = 30 \text{ V}, R_L = 0.5 \Omega$ $I_D = 60 \text{ A}, V_{GEN} = 10 \text{ V}, R_G = 2.5 \Omega$		12	30	ns
Rise Time ^c	t_r			11	30	
Turn-Off Delay Time ^c	$t_{d(\text{off})}$			25	50	
Fall Time ^c	t_f			15	30	
Source-Drain Diode Ratings and Characteristics ($T_C = 25^\circ\text{C}$)^a						
Continuous Current	I_s				60	A
Pulsed Current	I_{SM}				120	
Forward Voltage ^b	V_{SD}	$I_F = 60 \text{ A}, V_{GS} = 0 \text{ V}$			1.6	V
Reverse Recovery Time	t_{rr}	$I_F = 60 \text{ A}, \text{di}/\text{dt} = 100 \text{ A}/\mu\text{s}$		60		ns
Peak Reverse Recovery Current	$I_{RM(\text{REC})}$			6.0		A
Reverse Recovery Charge	Q_{rr}			0.4		μC

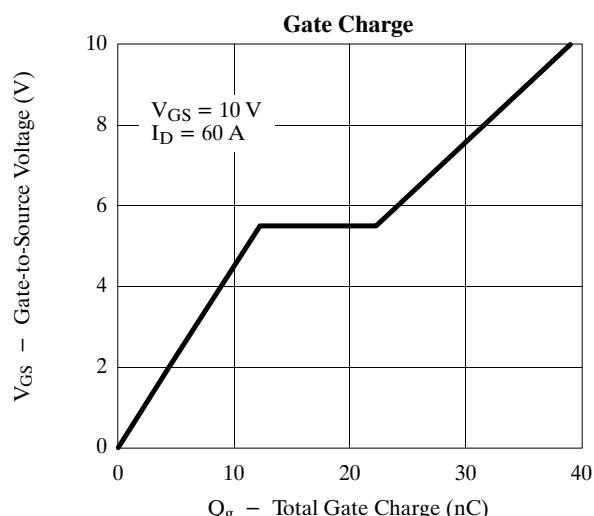
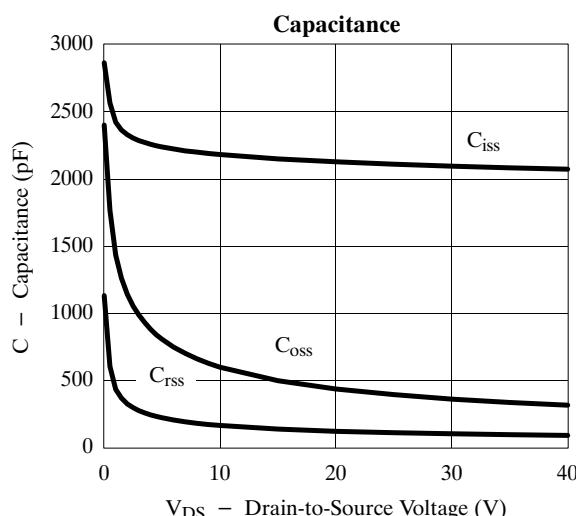
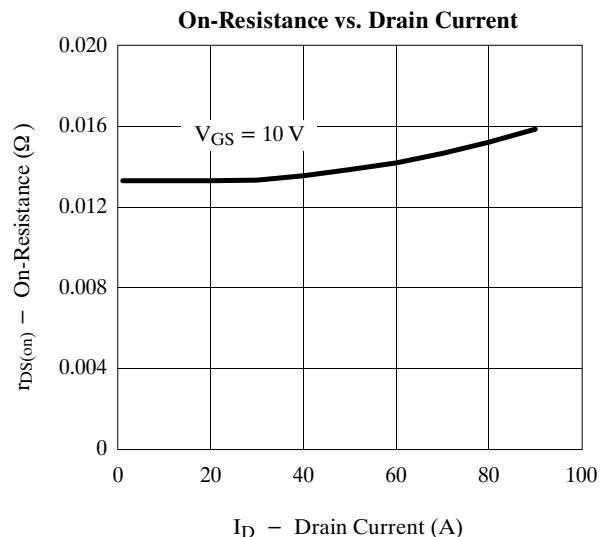
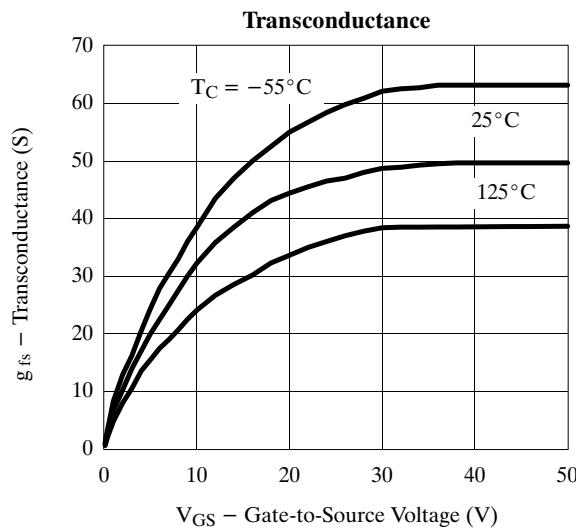
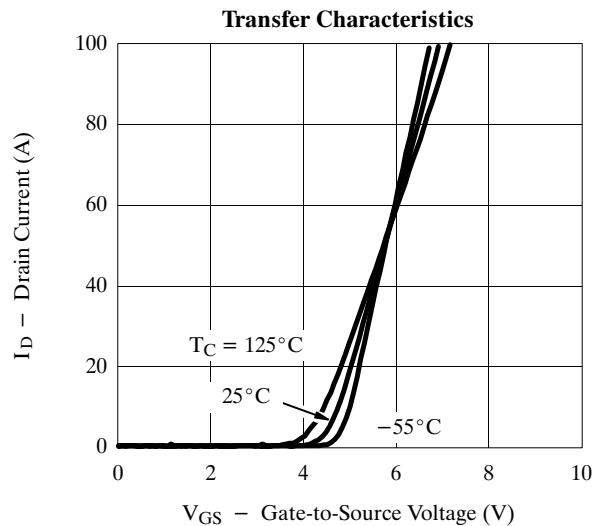
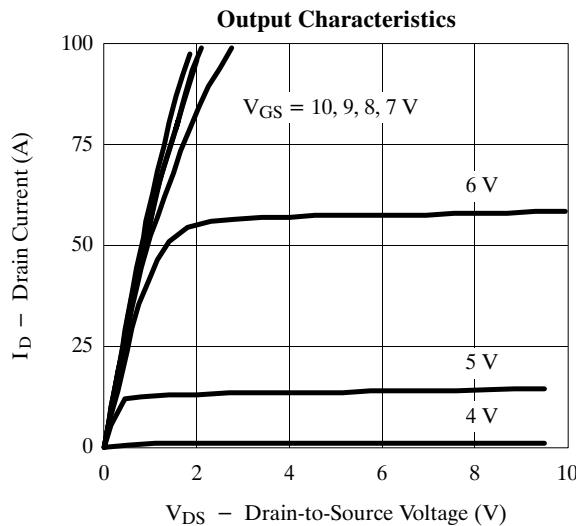
Notes:

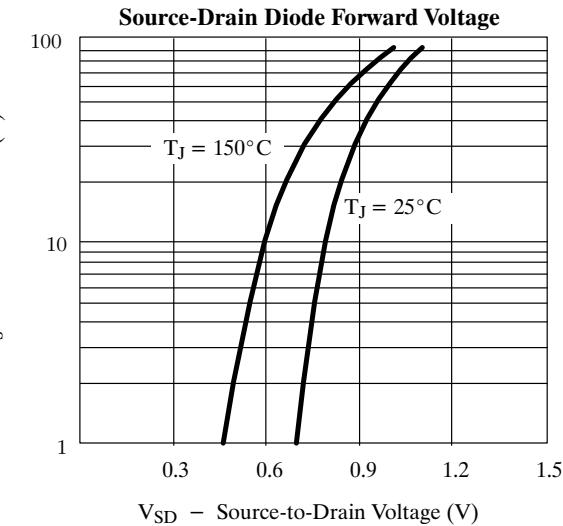
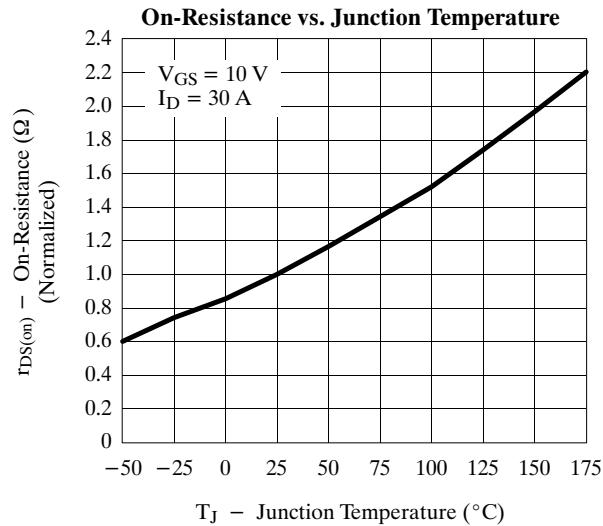
a. Guaranteed by design, not subject to production testing.

b. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.

c. Independent of operating temperature.

Typical Characteristics (25°C Unless Otherwise Noted)



SUP/SUB60N06-18**Typical Characteristics (25°C Unless Otherwise Noted)****Thermal Ratings**